Foreword

The “Phase Stability, Phase Transformation, and Reactive Phase Formation in Electronic Materials” symposium addresses the stability, transformation, and formation of phases during the fabrication, processing, and utilization of electronic materials and devices. Topics of interest include phase stability, transformations, and formation issues in microelectronic packaging technology, integrated circuit technology, and advanced electronic materials. This symposium has been an important and active part of the TMS annual meeting since 2002 and provides a platform for interaction and discussion among industrial experts and academic scholars from all over the world. This year was the eighth year of this symposium in the TMS annual meeting held February 15–19, 2009 in San Francisco, California. There were 46 oral presentations from various countries, and some of this research is found in this special issue of critically peer-reviewed papers. Readers should find the papers technologically valuable and of great scientific significance. The organizers are grateful to all the invited and contributed speakers for their participation in this symposium and acknowledge all the efforts of the authors and reviewers for making this special issue possible. The organizers especially thank Professor Suzanne Mohny, the editor-in-chief, for her assistance with the review and publication process.

Chih-ming Chen
National Chung Hsing University

Srinivas Chada
Medtronic Microelectronics

Sinn-wen Chen
National Tsing-Hua University

Hans Flandorfer
University of Vienna

A. Lindsay Greer
University of Cambridge

Jae-ho Lee
Hongik University

Kejun Zeng
Texas Instruments

Yee-wen Yen
National Taiwan University of Science and Technology

Wojciech Gierlotka
AGH University of Science and Technology

Chao-hong Wang
National Chung Cheng University